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1. **Minimal test configurations for FPGA local interconnects**  
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2. **Design and implementation of a parity-based BIST scheme for FPGA global interconnects**  
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3. **Testing Xilinx XC4000 configurable logic blocks with carry logic-modules**  
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6. **Configuration self-test in FPGA-based reconfigurable systems**  
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7. **Selecting built-in self-test configurations for field programmable gate arrays**  
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8. **On-wafer photoconductive sampling of MMICs**  
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9. **Test scheduling with loop folding and its application to test configurations with accumulators**  
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**10. Test configuration minimization for the logic cells of SRAM-based FPGAs: a case study**

Renovell, M.; Portal, J.M.; Figueras, J.; Zorian, Y.;  
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**11. SRAM-based FPGA's: testing the LUT/RAM modules**

Renovell, M.; Portal, J.M.; Figueras, J.; Zorian, Y.;  
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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	31	((test testing) near2 (configuration)).clm. and BIOS	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 06:22
L2	14	((test testing) near2 (configuration)).clm. and BIOS and (chip IC)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 07:27
L3	26	((test testing verif\$3) with (chip IC (integrated adj circuit))) same (configuration adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 07:29
L4	1751	((test testing) with configuration) and ((compare comparing compared comparison) near4 expect\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 08:46
L5	405	((test testing) with configuration) and ((compare comparing compared comparison) near4 expect\$4) and report	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 08:46
L6	270	((test testing) with configuration) and ((compare comparing compared comparison) near4 expect\$4) and report and difference	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 08:47
L7	183	((test testing) with configuration) and ((compare comparing compared comparison) near4 expect\$4) and report and difference	USPAT; IBM_TDB	OR	ON	2006/02/06 08:47
L8	5	(Wang and Jing-Rung).in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 08:59

S1	50	("5237690" "6287765" "6462998" "5659680" "5526364" "5793775" "5825700" "5950145" "6028798" "6307877" "6462584" "5671433" "5822610" "4244048" "6195775" "5021996" "5260946" "5717701" "5757820" "6158032" "6175529" "6239611" "4333142" "4833620" "4918691" "4961191" "5198758" "5228045" "5274648" "5323400" "5369643" "5513339" "5636163" "5661729" "5708601" "5781560" "5812472" "5838951" "5909453" "5912852" "5914902" "5995424" "6107821" "4283620" "4490673" "4597042" "4835704" "4860290" "4873669" "4940909").pn.	USPAT	OR	ON	2006/02/03 20:27
S2	16765	("5237690" "6287765" "6462998" "5659680" "5526364" "5793775" "5825700" "5950145" "6028798" "6307877" "6462584" "5671433" "5822610" "4244048" "6195775" "5021996" "5260946" "5717701" "5757820" "6158032" "6175529" "6239611" "4333142" "4833620" "4918691" "4961191" "5198758" "5228045" "5274648" "5323400" "5369643" "5513339" "5636163" "5661729" "5708601" "5781560" "5812472" "5838951" "5909453" "5912852" "5914902" "5995424" "6107821" "4283620" "4490673" "4597042" "4835704" "4860290" "4873669" "4940909").pn. test with configuration	USPAT	OR	ON	2006/02/03 20:28
S3	38	("5237690" "6287765" "6462998" "5659680" "5526364" "5793775" "5825700" "5950145" "6028798" "6307877" "6462584" "5671433" "5822610" "4244048" "6195775" "5021996" "5260946" "5717701" "5757820" "6158032" "6175529" "6239611" "4333142" "4833620" "4918691" "4961191" "5198758" "5228045" "5274648" "5323400" "5369643" "5513339" "5636163" "5661729" "5708601" "5781560" "5812472" "5838951" "5909453" "5912852" "5914902" "5995424" "6107821" "4283620" "4490673" "4597042" "4835704" "4860290" "4873669" "4940909").pn. and test with configuration	USPAT	OR	ON	2006/02/03 20:28

S4	38	("5237690" "6287765" "6462998" "5659680" "5526364" "5793775" "5825700" "5950145" "6028798" "6307877" "6462584" "5671433" "5822610" "4244048" "6195775" "5021996" "5260946" "5717701" "5757820" "6158032" "6175529" "6239611" "4333142" "4833620" "4918691" "4961191" "5198758" "5228045" "5274648" "5323400" "5369643" "5513339" "5636163" "5661729" "5708601" "5781560" "5812472" "5838951" "5909453" "5912852" "5914902" "5995424" "6107821" "4283620" "4490673" "4597042" "4835704" "4860290" "4873669" "4940909").pn. and (test with configuration)	USPAT	OR	ON	2006/02/03 20:28
S5	7	("5237690" "6287765" "6462998" "5659680" "5526364" "5793775" "5825700" "5950145" "6028798" "6307877" "6462584" "5671433" "5822610" "4244048" "6195775" "5021996" "5260946" "5717701" "5757820" "6158032" "6175529" "6239611" "4333142" "4833620" "4918691" "4961191" "5198758" "5228045" "5274648" "5323400" "5369643" "5513339" "5636163" "5661729" "5708601" "5781560" "5812472" "5838951" "5909453" "5912852" "5914902" "5995424" "6107821" "4283620" "4490673" "4597042" "4835704" "4860290" "4873669" "4940909").pn. and (test with configuration with set\$4)	USPAT	OR	ON	2006/02/03 20:30
S6	376	(test testing) near2 (configuration with set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 20:31
S7	16	(test testing) near2 (configuration with set\$4) and BIOS	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 08:59
S8	3	((test testing) near2 (configuration with set\$4)).clm. and BIOS	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 06:22